MSKSEMI 美森科













FSD

'S

TSS

MOV

GDT

PLED

2SC4226

Product specification





Features

- CollectorCurrentCapabilityIc=100mA
- CollectorEmitterVoltageVcEo=12V



Classification of hfe

Туре	2SC4226 R23-MS	2SC4226 R24-MS	2SC4226 R25-MS
Range	40-80	70-140	125-250
Marking	R23	R24	R25

AbsoluteMaximumRatingsTa=25 $^{\circ}$ C

Parameter	Symbol	Rating	Unit
Collector - Base Voltage	Vcво	20	
Collector - Emitter Voltage	Vceo	12	V
Emitter - Base Voltage	V _{EBO}	3	
Collector Current - Continuous	lc	100	mA
Collector Power Dissipation	Pc	150	mW
Junction Temperature	Тл	150	
Storage Temperature Range	Tstg	-65 to 150	${\mathbb C}$

ElectricalCharacteristicsTa=25℃

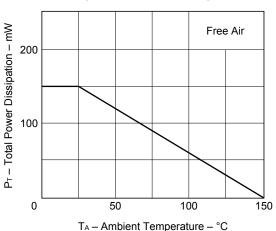
Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Collector- base breakdown voltage	Vсво	Ic= 100 μA , IE= 0	20			
Collector- emitter breakdown voltage	VCEO	Ic= 1 mA , I _B = 0	12			V
Emitter - base breakdown voltage	VEBO	IE= 100 μA, IC= 0	3			\ \
Collector-base cut-off current	Ісво	VcB= 10 V , IE= 0			1	
Emitter cut-off current	І ЕВО	VEB= 1V , IC=0			1	uA
Collector-emitter saturation voltage	VCE(sat)	Ic=100 mA, I _B =10mA			0.5	
Base - emitter saturation voltage	VBE(sat)	Ic=100 mA, I _B =10mA			1.2	V
DC current gain	hfE	VcE= 3V, Ic= 7mA	40		250	
Insertion Power Gain	S21e ²	VcE= 3V, Ic= 7mA,f=1GHz	7			
Noise Figure	NF	VcE= 3V, Ic= 7mA,f=1GHz			2.5	dB
Feedback Capacitance	Cre	VcE= 3V, IE=0,f=1MHz			1.5	pF
Transition frequency	fτ	VcE= 3V, Ic= 7mA	4.5			GHz

 $Note. Pulse Measurement; PW \leq 350 us, Duty Cycle \leq 2\% Pulsed.$

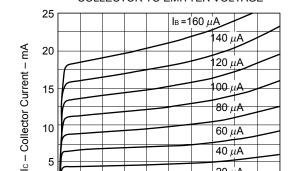


Typical Characterisitics





COLLECTOR CURRENT vs.
COLLECTOR TO EMITTER VOLTAGE

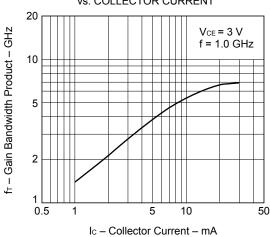


5
VcE – Collector to Emitter Voltage – V

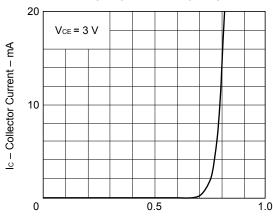
20 μΑ

10

GAIN BANDWIDTH PRODUCT vs. COLLECTOR CURRENT

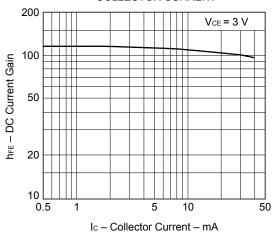


COLLECTOR CURRENT vs. BASE TO EMITTER VOLTAGE

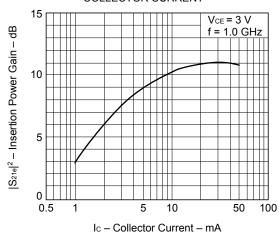


V_{BE} – Base to Emitter Voltage – V

DC CURRENT GAIN vs. COLLECTOR CURRENT



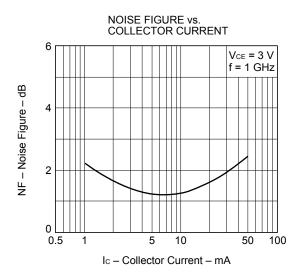
INSERTION POWER GAIN vs. COLLECTOR CURRENT

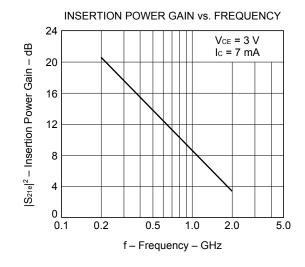


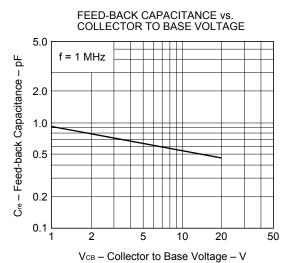
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Typical Characterisitics

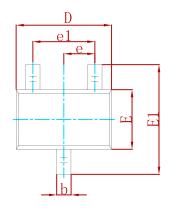


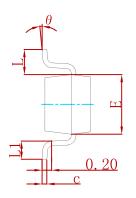


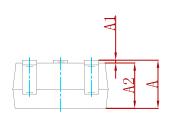




PACKAGEMECHANICALDATA

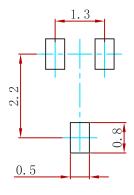






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.100	0.035	0.043	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.000	0.035	0.039	
b	0.200	0.400	0.008	0.016	
С	0.080	0.150	0.003	0.006	
D	2.000	2.200	0.079	0.087	
E	1.150	1.350	0.045	0.053	
E1	2.150	2.450	0.085	0.096	
е	0.650 TYP		0.026 TYP		
e1	1.200	1.400	0.047	0.055	
L	0.525 REF		0.021	REF	
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
2SC4226	SOT-323	3000



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